

Simulation Study of GEM gating for LC-TPC

Akira Sugiyama (Saga Univ.)

LC-TPC Asia group +

Japan

Saga: A.Aoza, T.Higashi, A.Ishikawa, A.Sugiyama, H.Tsuji

Kinki: Y.Kato, K.Hiramatsu, T.Yazu

Kogakuin: T.Watanabe

TUAT: O.Nitoh, H.Ohta, K.Sakai, H.Bito

KEK: K.Fujii, K.Kobayashi, H.Kuroiwa, T.Matsuda, R.Yonamine, S.Uno

China

Tsinghua: Y.Gao, Y.Li, J.Li, L.Cao, Z.Yang

Philippines

MSU: A.Bacala, C.J.Gooc, R.Reserva, D.Arogancia



Gating for back-drift ions

ILC case : ions feedback must be smaller than 10^{-3} (ie. no ions from MPGD)

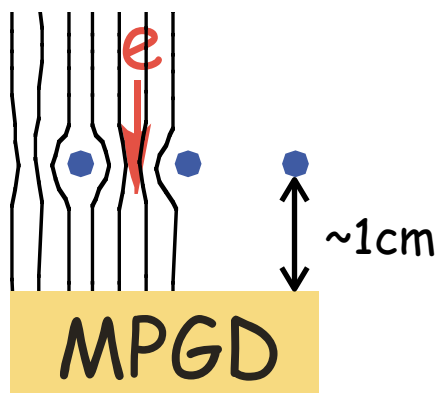
Gate can be open for 1 msec and be closed following 199 msec.

ion can drift < 1cm

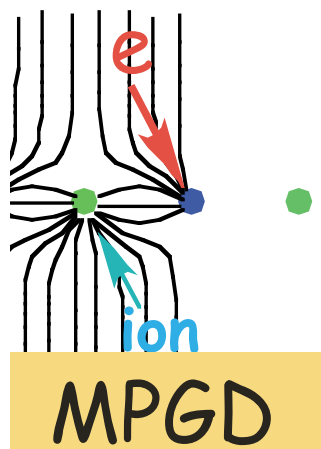
Gate: wire

3 candidates

open

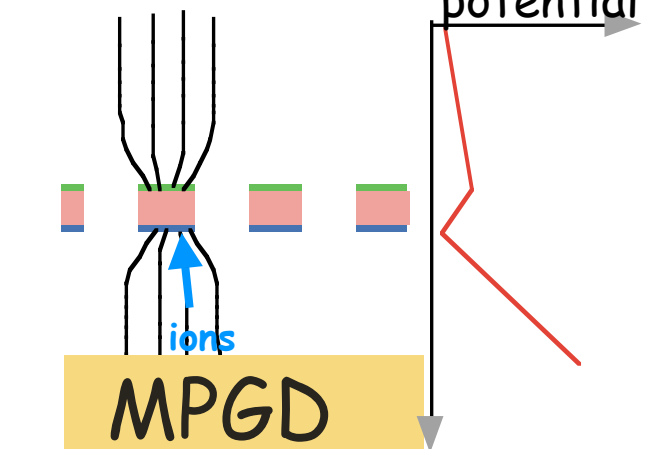
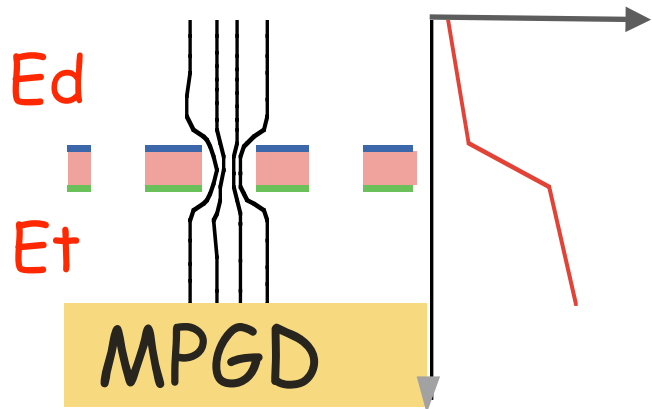


close



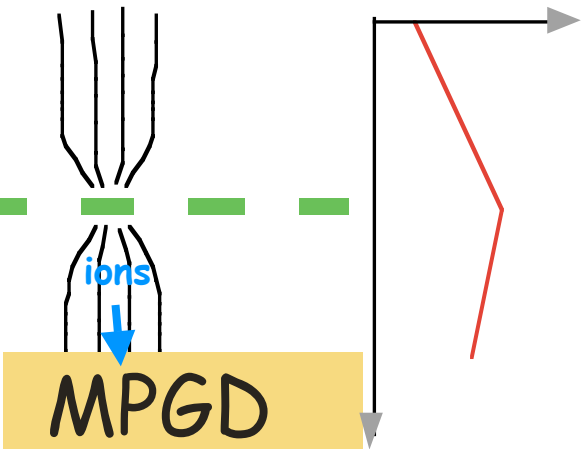
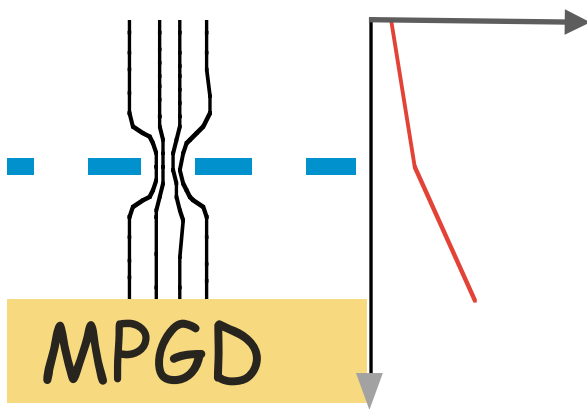
local change of E
wire tension
 $E \times B$

GEM



local change of E
electron transmission

micromesh



change of drift E
electron transmission

GEM gating

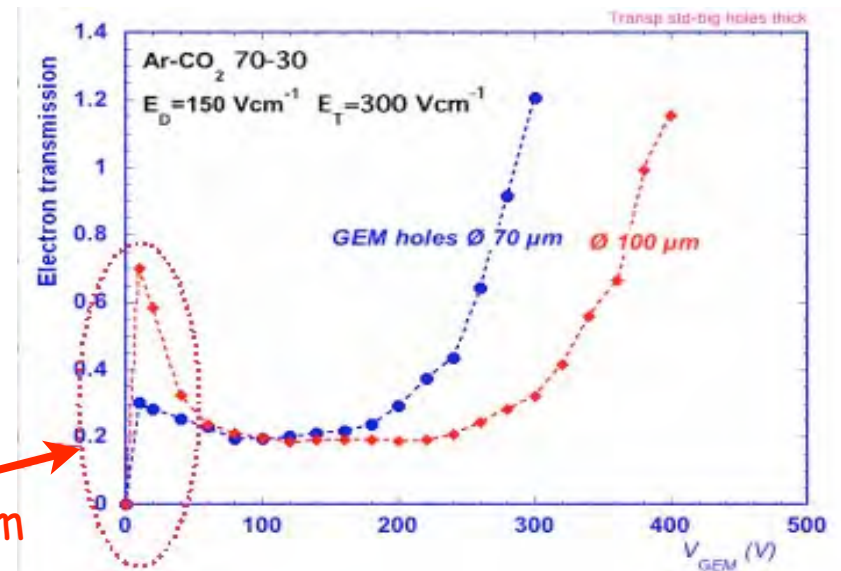
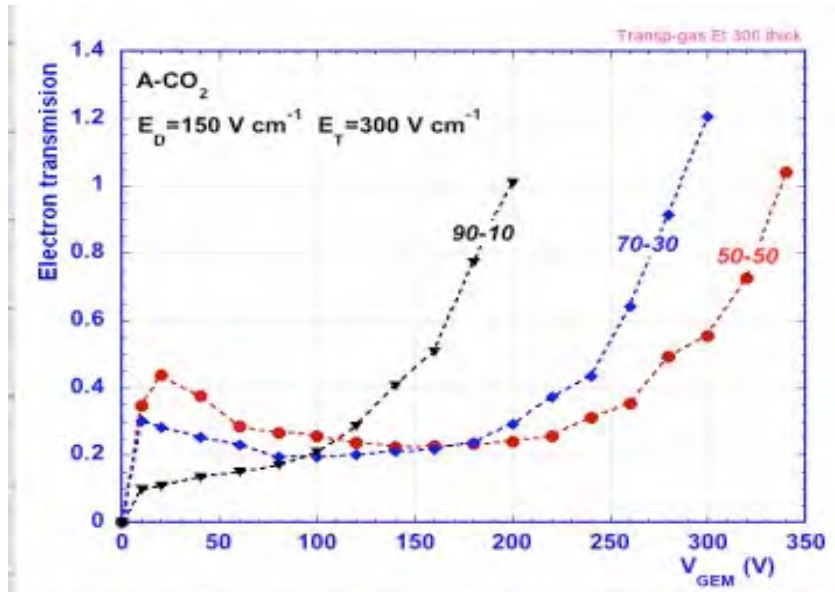
F. Sauli had proposed GEM as gating device @LBLTPC'06

electron transmission is the key issue here !!

Electron transmission had been measured as a function of V_{GEM}

for different Gas mixture

for different hole size



Low voltage operation may give us good electron transmission:
where no gas amplification happens.

We hope to understand this mechanism and optimize GEM for ILC gate

E field calculation and electron simulation in gas help us to do this.

Maxwell3D

Garfield

BUT We have to make sure these tools provide correct answer

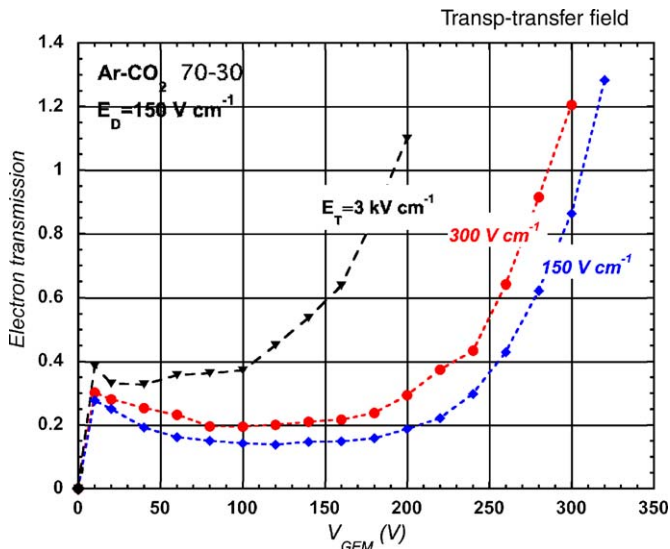


Fig. 4. Electron transmission of a standard GEM foil, measured in the pulse mode, for standard high (3 kV cm^{-1}) and low transfer fields (150 and 300 V cm^{-1}), as a function of GEM voltage. Drift field: 150 V cm^{-1} , gas filling A-CO₂ 70-30 at STP.

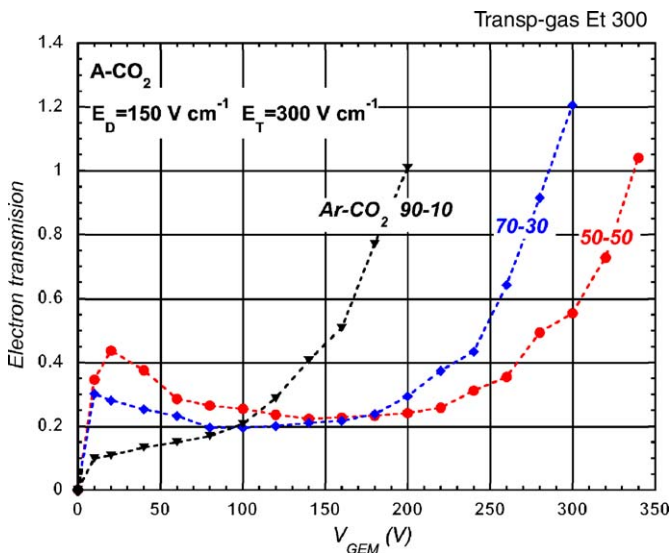
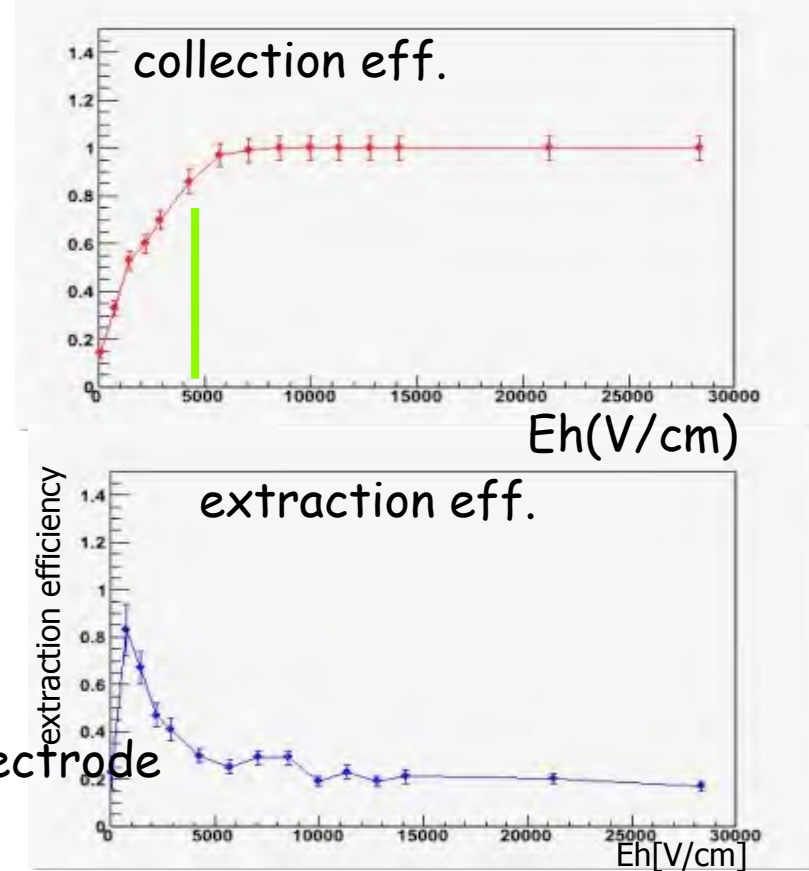


Fig. 5. Electron transmission of a standard GEM, for low transfer field (300 V cm^{-1}), as a function of GEM voltage and for three A-CO₂ mixtures: 90-10, 70-30 and 50-50.

Collection eff. has been studied by several groups
as a func. of E_d/E_h
and known to be ~ 1 @ $E_d/E_h < 0.03$ (ie 4.5kV/cm here)
it is relaxed when hole become larger.



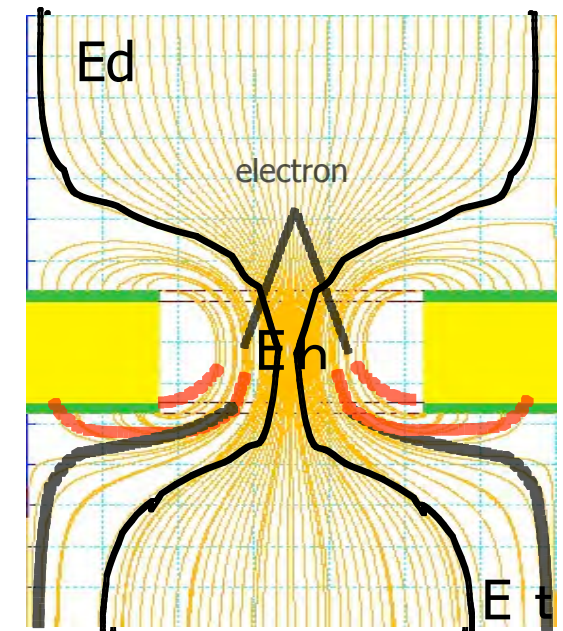
Extraction eff. behave more complicatedly

- area of penetrating field line become small as E_h
- electron can spread due to diffusion(E_h)
- some electron follow returned filed line to GEM electrode

area of penetrating field line is larger @ low E_h
higher extraction
diffusion behavior is also important !

This means "transmission is largely depend on gas"

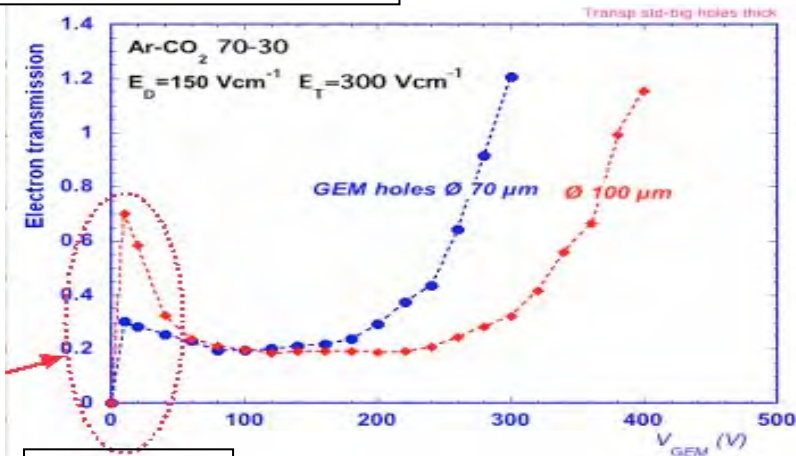
LC also requires High Magnetic Field (3~4 T)



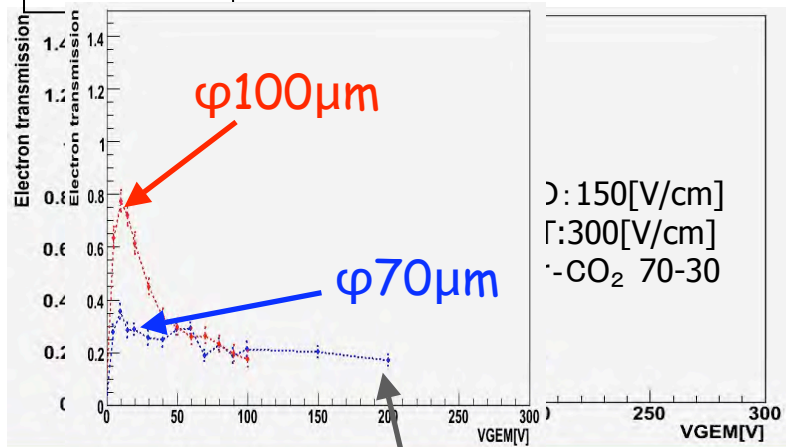
Comparison to exp. results

Electron transmission
Hole size dep.

Measurement by Sauli

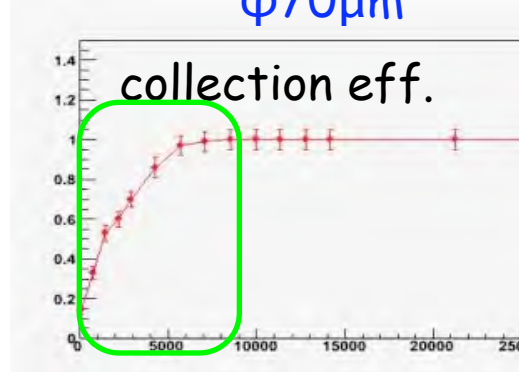


simulation

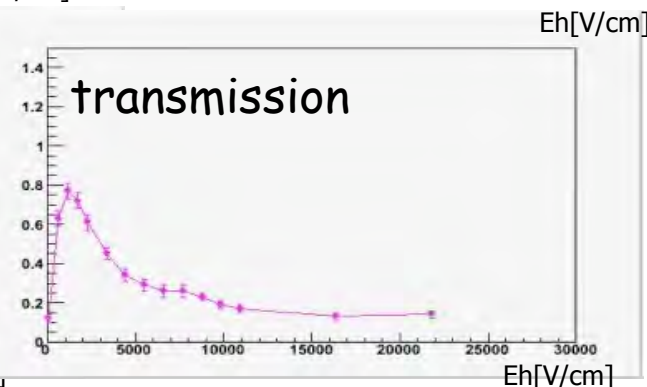
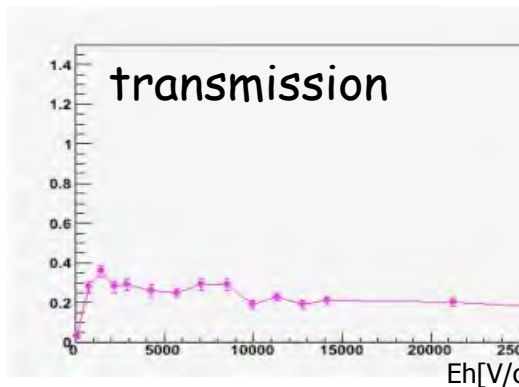
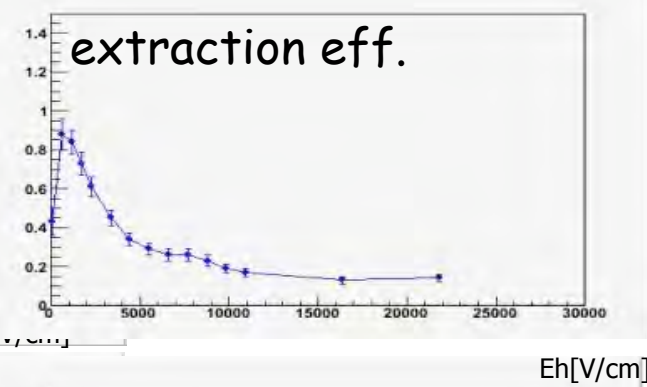
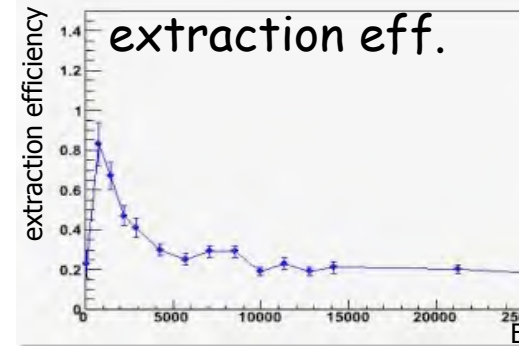
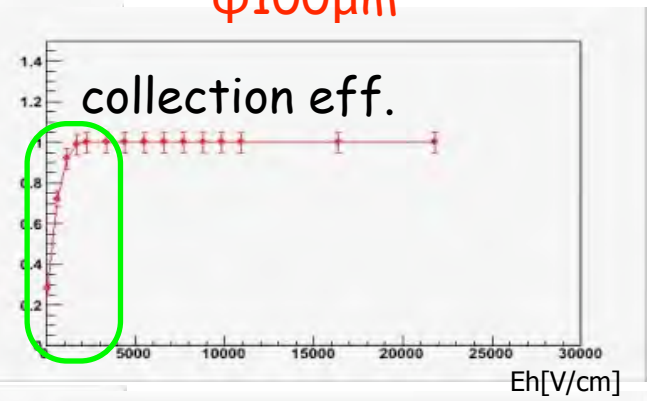


Gas gain is not included

ϕ 70 μm

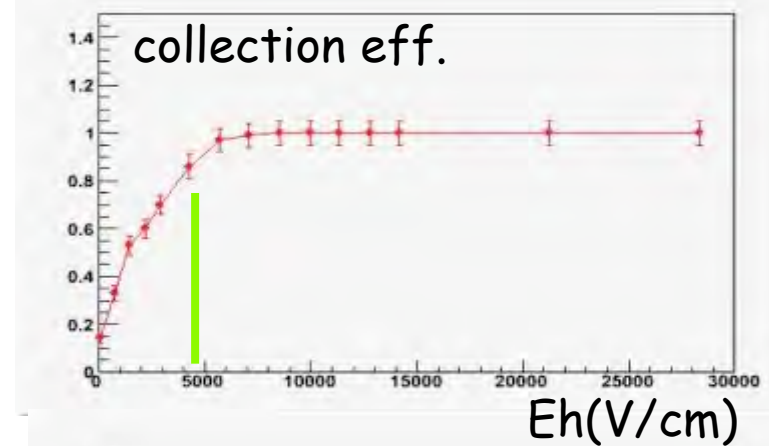


ϕ 100 μm



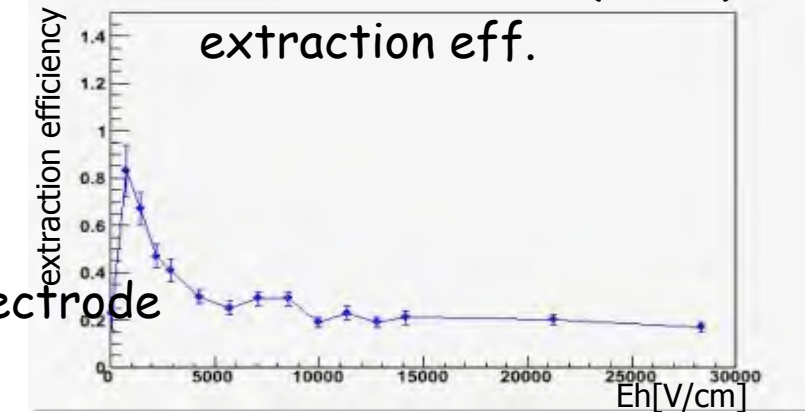
Collection eff. improve transmission
due to large aperture

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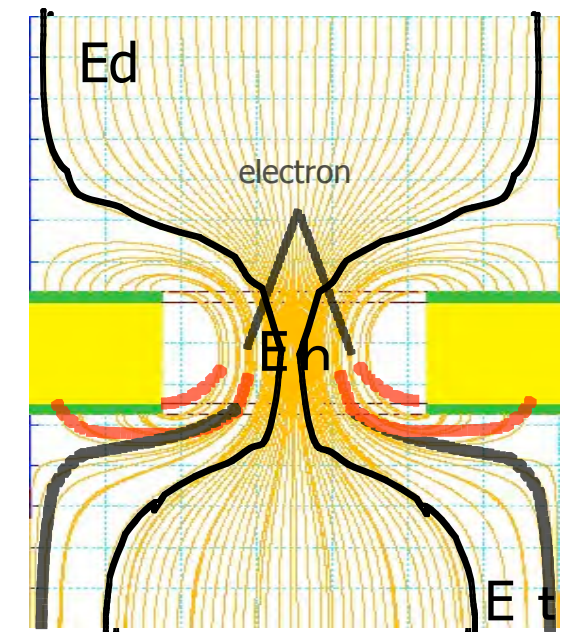
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Optimization of GEM Gating for LC-TPC

High Magnetic Field (3 ~ 4 Tesla)

High ωT gas

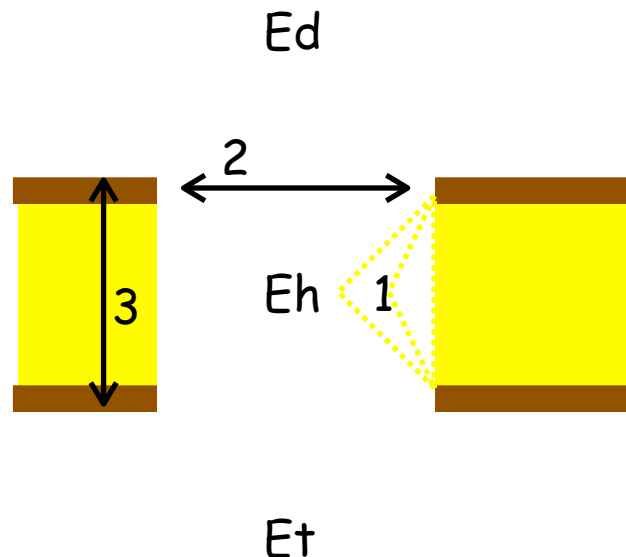
Ar:CF₄ is the first candidate for this (w/ iso-C₄H₁₀)

Optimization of GEM itself

1. Hole shape
2. Hole Size/pitch
3. thickness

Optimization of operation condition

1. Drift E field : E_d
2. Hole E field (V_{GEM}) : E_h
3. transfer E field : E_t



Summary of simulation study

If GEM would be used for GATE, it must be

Aperture must be large (larger hole size)

Thinner GEM is better for Gating

Field shaping around hole

E_h need to be kept low (diffusion)

E_d must be low (50V/cm)

E_t must be high (300V/cm) (but just below diffusion rise)

We may be able to achieve 70% transmission @25um thick GEM in simulation.

Do you accept this number ??

(10% error may exist)

Confirmation is necessary ! especially under High B field

Need to establish how to measure.

25um thick GEM is available (though hole diameter is 90 um)

Do we try 12.5um for 10% improvement ?

DESY 5T magnet is necessary for this

Let's do together